

208546US-2-S



IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF:

MASAHIRO TANAKA

: EXAMINER: (TO BE ASSIGNED)

SERIAL NO: 09/853,661

FILED: MAY 14, 2001

: GROUP ART UNIT: (TO BE ASSIGNED)

FOR: ELECTRODE CONTACT SECTION OF
SEMICONDUCTOR DEVICE

#4/a
6/27/2
mule

PRELIMINARY AMENDMENT

ASSISTANT COMMISSIONER FOR PATENTS
WASHINGTON, D.C. 20231

SIR:

IN THE CLAIMS

Before examining the captioned patent application, please amend the claims as shown in the Attachment, in which underlining and bracketing show the changes introduced into the previously-pending claims to arrive at the clean claims provided below:

Sub Bn
X
1. (Amended) An electrode contact section incorporated in a semiconductor device, comprising:

a first-conductivity-type semiconductor substrate;
a second-conductivity-type impurity layer formed in one surface of the semiconductor substrate and having a thickness of not more than 1.0 μm from a surface of the semiconductor substrate;

a second-conductivity-type contact layer formed in the impurity layer and having a thickness of not more than 0.2 μm from the surface of the semiconductor substrate, the contact

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